



IDENTIFYING DATA

Integrated Circuits Design and Manufacturing

Subject	Integrated Circuits Design and Manufacturing			
Code	V05M145V01215			
Study programme	Telecommunication Engineering			
Descriptors	ECTS Credits	Choose	Year	Quadmester
	5	Optional	1st	2nd
Teaching language	Spanish			
Department				
Coordinator	Fariña Rodríguez, José			
Lecturers	Cao Paz, Ana María Fariña Rodríguez, José			
E-mail	jfarina@uvigo.es			
Web				
General description	<p>The objectives in mind are:</p> <ol style="list-style-type: none"> 1) To know and understand the design methodologies of Integrated Circuits (ICs) based on CMOS technology. 2) To know the basic topologies used in analog electronic circuits. 3) To know how to analyze and dimensioning the devices of the basic topologies of analog circuits in CMOS technology. 4) To know and be capable to use software tools for the design of integrated circuits. 5) To know to specify an integrated circuit for manufacturing in CMOS technology. 			

Competencies

Code	
A4	CB4 Students must communicate their conclusions, and the knowledge and reasons stating them-, to specialists and non-specialists in a clear and unambiguous way.
A5	CB5 Students must have learning skills to allow themselves to continue studying in largely self-directed or autonomous way
B8	CG8 The ability to apply acquired knowledge and to solve problems in new or unfamiliar environments within broader and multidiscipline contexts, being able to integrate knowledge.
C10	CE10 The ability to design and manufacture integrated circuits.

Learning outcomes

Expected results from this subject	Training and Learning Results
Know the design methodologies of electronic integrated circuits	C10
Know the basic topologies used in analog electronic circuits	C10
Can analyze and dimension the devices that form the basic topologies of analog circuits	A5 B8 C10
Know aid software tools integrated circuit design	C10
Know how an electronic circuit is specified for manufacturing	A4 C10

Contents

Topic	
Chapter 1: Introduction (1h)	Course introduction. Objectives and course planning. Basic concepts of microelectronic design of integrated circuits (ICs).

Chapter 2: Manufacturing sequence for ICs (1h)	Introduction to ICs manufacturing. Planar technology. Manufacturing sequence of ICs in CMOS technology. Structure of MOS transistors. Manufacturing example: CMOS inverter. Masks pattern (layout). Technological design rules. Methodologies and tools for design assistance.
Chapter 3: Physical structure of basic devices and routing strategies (1h)	Specification of the physical structure of MOS transistor. Specification of the physical structure of a resistor. Specification of the physical structure of a capacitor. Strategies for performing transistors with high aspect ratio. Strategies for matched transistors.
Chapter 4: Basic amplifier topologies (2h)	Common source topology. Common drain topology. Common gate topology. Cascode topology. Push_Pull amplifier. Physical design examples.
Chapter 5: Current mirror (3h)	Current sources. Basic structure of a current mirror. Analysis of functioning. Frequency response. Cascode topology. Physical design examples.
Chapter 6: Differential pair (3h)	Differential pair structure. DC analysis. AC analysis. Specifications and design of the physical structure of a self-biased differential amplifier topology. Common mode rejection ratio. Matching of transistors. Slew rate limitations. Physical design examples.
Chapter 7: Operational amplifier (2h)	Two stages operational amplifier. Design parameters. Operational Transconductance Amplifier (OTA). Examples of physical designs.
Chapter 8: Preparing for manufacturing (2h)	Distribution in the base plane. Pad and terminals. Specification formats. Packages.
Laboratory session 1: Introduction to design tools for ICs (2h)	Introduction to design tools for analog ICs. Current mirror example. Electric simulation. Design Rules Check (DRC) and layout extraction.
Laboratory session 2: Design of self-biased differential pair (2h)	Electrical specification. Characterization of DC operating parameters. Characterization of AC operating parameters.
Laboratory session 3: Design of self-biased differential pair II (2h)	DRC and layout extraction. Layout versus schematic (LVS). Post-layout simulation.
Laboratory session 4: Design of a transconductance amplifier (2h)	Electrical Specification. Physical specification. Operation testing.
Laboratory session 5: Preparing for manufacturing (2h)	For the circuit obtained in Laboratory session 4, perform the required steps to create the information needed in order to send the circuit to manufacture.

Planning

	Class hours	Hours outside the classroom	Total hours
Master Session	14	28	42
Troubleshooting and / or exercises	4	28	32
Laboratory practises	9	22.5	31.5
Short answer tests	1	4	5
Troubleshooting and / or exercises	1	5.5	6.5
Practical tests, real task execution and / or simulated.	1	7	8

*The information in the planning table is for guidance only and does not take into account the heterogeneity of the students.

Methodologies

	Description
Master Session	The professor will present the relevant concepts of the course. Before each lecture, students must carry out a preparation analysis of the topics to be addressed. The aim is to encourage active participation of students, who may ask questions or expose doubts during the session. For a better understanding of certain content, practical examples or case studies will be discussed
Troubleshooting and / or exercises	Students will work in small teams (C-type groups) in the physical design and characterization of a circuit consisting of active devices and passive components, under the close guidance of professors. Attendance will be recorded. The activities to be developed by each team are: - Analysis of possible solutions and design alternatives.
Laboratory practises	Students work in groups of two people. They will work with IC CAD tools for IC design, in which they will carry out the definition of an electronic circuit both electrical and physical level, the verification of compliance with specifications and design preparation for manufacturing. Attendance will be recorded and performance of each group in each lab assignment will be evaluated.

Personalized attention

Methodologies	Description
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Master Session	The teaching staff will attend doubts and enquiries of the students about the theoretical contents, previous preparation of laboratory practices as well as its contents. Professors will also resolve the doubts and enquiries of students about specifications, theoretical and practical aspects of the assigned project as well as those about the content and structure of the explanatory report. In addition, students will be guided about the structure and contents of the sessions of presentation and defense of the results achieved in the project. Students will have the opportunity to attend personalized or group mentoring.
Laboratory practises	The teaching staff will attend doubts and enquiries of the students about the theoretical contents, previous preparation of laboratory practices as well as its contents. Professors will also resolve the doubts and enquiries of students about specifications, theoretical and practical aspects of the assigned project as well as those about the content and structure of the explanatory report. In addition, students will be guided about the structure and contents of the sessions of presentation and defense of the results achieved in the project. Students will have the opportunity to attend personalized or group mentoring.
Troubleshooting and / or exercises	The teaching staff will attend doubts and enquiries of the students about the theoretical contents, previous preparation of laboratory practices as well as its contents. Professors will also resolve the doubts and enquiries of students about specifications, theoretical and practical aspects of the assigned project as well as those about the content and structure of the explanatory report. In addition, students will be guided about the structure and contents of the sessions of presentation and defense of the results achieved in the project. Students will have the opportunity to attend personalized or group mentoring.

Assessment				
	Description	Qualification	Training and Learning Results	
Short answer tests	As part of the continuous evaluation, it will take place in mid-course an individual written test of 30 minutes, in one of the lecture sessions. This test will involve 10% of the final grade. This test is the last chance for students to decide whether or not they opt for continuous evaluation. All students completing the test implicitly choose to follow continuous evaluation. The remaining students have to explicitly declare their choice. The lack of declaration from a student means he/she will not follow continuous evaluation. Another written test of 60 minutes will be held in the date of the final exam. This test will have two parts and it is compulsory in whole for students not in continuous evaluation. Students in continuous evaluation can also voluntarily complete the first part since the contents correspond to the first written test. In that case, the score they will receive in this part of the course evaluation will be the one achieved in this second test. The second part of the test is mandatory for all students. Each of the parts will involve 10 % of the final qualification. To pass the course, students must achieve in each part a mark of 4 or higher in a 0-10 scale (or in the intermediate test, where appropriate). Competences CE10 and CB4 will be assessed in these tests.	20	A4	C10
Troubleshooting and / or exercises	As part of the continuous evaluation, it will take place in mid-course an individual written test of 30 minutes, in one of the lecture sessions. This test will involve 10% of the final grade. This test is the last chance for students to decide whether or not they opt for continuous evaluation. All students completing the test implicitly choose to follow continuous evaluation. The remaining students have to explicitly declare their choice. The lack of declaration from a student means he/she will not follow continuous evaluation. Another written test of 60 minutes will be held in the date of the final exam. This test will have two parts and it is compulsory in whole for students not in continuous evaluation. Students in continuous evaluation can also voluntarily complete the first part since the contents correspond to the first written test. In that case, the score they will receive in this part of the course evaluation will be the one achieved in this second test. The second part of the test is mandatory for all students. Each of the parts will involve 10 % of the final qualification. To pass the course, students must achieve in each part a mark of 4 or higher in a 0-10 scale (or in the intermediate test, where appropriate). Competences CE10 and CB4 will be assessed in these tests.	20	A4	B8 C10

Practical tests, real task execution and / or simulated.	<p>The evaluation of the practical tests will be performed from memory supporting and public presentation of results. Each group of students you must submit a report of the work has been carried out, indicating expresses the contribution of each to the whole, as well as methodology followed for the distribution and coordination of tasks. The evaluation of the work will be based on the following aspects:</p> <ul style="list-style-type: none"> - Analysis of alternatives - Correct implementation and design verification - Design compaction - Use of appropriate strategies to minimize the effects of imperfections in the manufacturing process and to ensure good matching of the electrical characteristics between components or devices that like this require it by functional reasons. - Information for integrated circuit manufacturing. - Formal aspects: clarity and order, including figures and appropriate and outstanding data, as well as explanations in a concrete and comprehensive way. <p>Each student will have an individual public exposure of the project has personally performed (including tasks planning and coordination if applicable). The presentations of the students from each group will be out in the same session, 1 hour. Each student will have 5 minutes for their presentation. At the end of the presentation, students must answer questions from teachers and other students present. The evaluation will be based on both the content and formal aspects of the presentation and the answers to questions. It may also assess positively to students who perform relevant questions. The explanatory report should be submitted at least two days before public presentation of work. To pass the course, the student will need obtain at least a score of 5 over 10 in memory, get to least a score of 5 out of 10 in public presentation. In the evaluation of the practical tests, the memory note will weigh 70% and the presentation 30%. In this test the CE10, CB4, CB5 and CG8 skills are evaluated.</p>	60	A4 B8 C10 A5
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Other comments on the Evaluation

- Final test will be 50% of the overall grade of the course. It will consist of two parts: short answer questions and resolution of problems. The part of the questions will represent 40 % of the test qualification and the part of resolution of problems the other 60%. In order to calculate the grade it is necessary to obtain at least 50 % of the maximum score for each part.

- They must develop a project, and deliver the corresponding report and public presentation (in the same sessions and with the same criteria as students in continuous evaluation). Reports are due two days before the public presentation. The project qualification will involve 50% of the overall grade of the course. In the final qualification of the project, the memory report has a corresponding percentage of 70% and the other 30% is obtained from the qualification of the presentation. In order to calculate the grade it is necessary to obtain at least 50 % of the maximum score for each part.

Students not passing the course in the first call will have the opportunity to attend a second call. To pass the course, students must achieve in each part at least 50 % of the maximum score.

Sources of information

R. Jacob Baker, **CMOS Circuits desing, Layout and Simulation**, John Wiley & Sons,
Paul R. Gray, Paul J. Hurst, Stephen H. Lewis, Robert G. Meyer, **Analysis and Design of Analog Integrated Circuits**, John Wiley & Sons,
Behzad Razavi, **Design of Analog CMOS Integrated Circuits**, McGraw Hill,
Stephen A. Campbell, **Fabrication Engineering at the micro-and nanoscale**, Oxford University Press,

Recommendations